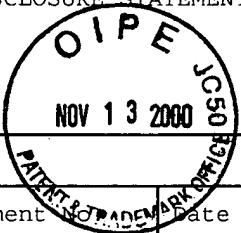


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				Atty. Docket No. FUK-63		Serial No. 09/402,112		
				Applicant Shojiro KAWAKAMI et al.				
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							Yes	No
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				Applicant Shojiro KAWAKAMI et al.				
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